Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/003,557	CHANG ET AL.	
Examiner	Art Unit	
Nhon T. Diep	2621	

SEARCHED						
Subclass	Date	Examiner				
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	1				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Fast Search	10/13/166	W.D.		